# SISS13 Program

**June 23, 2011 (Thu)**

12:25- Opening remarks

**High sensitive detection by laser ionization** 12:30-13:40

**Matrix effect-free depth profiling of multilayered samples by resonance enhanced multiphoton ionization sputtered neutral mass spectrometry**

S. Nishinomiya, N. Kubota, S. Hayashi and H. Takenaka

**Multi-element quantitative analysis of Genesis solar wind collectors with Resonance Ionization Mass Spectrometer (Invited talk)**

I. Veryovkin

**Laser Post-Ionization Secondary Neutral Mass Spectrometry for nanometer scale materials characterization**

I. Veryovkin

(Break)

**D-SIMS** 13:50-15:50

**Precise baddeleyite Pb/Pb and U/Pb isotopic age Determination by Cameca 1280 SIMS (Invited talk)**

X.-H. Li, Q.-L. Li, Y. Liu, G.-Q. Tang and J.-H. Yang

**SIMS analysis of extraterrestrial materials including the HAYABUSA mission samples (Invited talk)**

H. Yurimoto

**SIMS Depth Profiling of Ultra-shallow Implants with Oxygen Primary Ions (Invited talk)**

Y. Kataoka

**Vender session: CAMECA**

M. Schuhmacher

(Break)

**TOF-SIMS** 16:00-17:30

**ToF-SIMS Imaging Analysis of Biological Samples (Invited talk)**

T. G. Lee

**Application of TOF-SIMS to the direct determination of plant components and introduction of CryoTOF-SIMS/SEM complex apparatus (Invited talk)**

K. Fukushima, K. Saito and K. Kuroda

**Vender session: ION-TOF "Recent TOF-SIMS and LEIS Developments at ION-TOF"**

M. Terhorst

**——————-**

**June 23, 2011 (Thu)**

**Poster session** 17:30-19:00

P-1. **TOF-SIMS discrimination of PE / PP thin contamination using multivariate analysis**

K. Usugi,

P-2. **TOF-SIMS Analysis of Boron and Nitrogen in Steels**

K. Kusama, S. Naya, R. Sato and N. Usuki

P-3. **An effect of measurement conditions on the depth resolution for TOF-SIMS depth profiling**

A. Murase, T. Mitsuoka, M. Tomita, H.Nonaka, H. Takenaka, and H.Morita

P-4. **Characterization of the protein damages on the outermosthair surface using TOF-SIMS**

M. Okamoto, K. Ishikawa, N. Tanji and S. Aoyagi

P-5. **A New Time of Flight SIMS Instrument for3-Dimensional Imaging and Analysis Using Cluster Ion Beams**

R. Hill, R. Oiwa, J. S. Fletcher and J. C. Vickerman

P-6. **Continuous and Automatic Imaging Analysis on Cutting Cross-Sections of Particulate Matters by FIB-TOF-SIMS**

Takahiro Kashiwagi, J. Nakagawa, T. Sakamoto

P-7. **Converging of argon cluster ion beams with a glass capillary**

K. Shoji, K. Iuchi, K. Moritani, N. Inui, and K. Mochiji

P-8. **Ion Bean Stimulated Desorption**

T. Kobayashi, S. Toda,Y. Kuwahara and K. Ueda

P-9. **Light emission from sputtered or backscattered atoms on tungsten surfaces irradiated by $Kr^+$ ions**

N. Nogami, K. Furuya, D. Kato, T. Kenmotsu, K. Motohashi, Y. Sakai, and H. A. Sakaue

—————-

**June 24, 2011 (Fri)**

**Atom Probe** 10:00-11:20

**Anomalous distribution in atom probe tomography data of solute carbon in ferrous steel**

Y. Kobayashi, J. Takahashi and K. Kawakami

**Combined Analyses of Atom probe tomography and nano-SIMS for the Interface Segregation in Steels (Invited talk)**

C. G. Park

**Vender session: CAMECA**

P. Clifton

(Break)

**Novel primary ion beam** 11:30-12:20

**High sensitive SIMS with electrospray droplet impact method**

S. Ninomiya, L.C. Chen, Y. Sakai and K. Hiraoka

**Ambient surface mass spectrometry – developing the metrology for reliable and repeatable measurement (Invited talk)**

I. Gilmore

(12:20-13:20 Lunch)

**G-SIMS** 13:20-14:10

**Investigation of G-SIMS Analysis for PEG samples**

I. Mihara, M. Kudo and S. Aoyagi

**Watching chemistry in 3D & hi-definition using SIMS – from nanostructures to informatics (Invited talk)**

I. Gilmore

**Cluster Ion Beam** 14:10-16:30

**Surface sensitive analysis of organic thin films by Ar-gas cluster SIMS**

K. Moritani, N. Inui, K. Mochiji

**Organic Depth Profiling Using Cluster Beams: $C_{60}$ and Large Ar Clusters**

D. Rading, R. Moellers, M. Terhorst, E. Niehuis

(Break)

**Organic and Biological Material Analysis with Cluster Ion Beams (Invited talk)**

J. Matsuo

**Clinical applications of SIMS and MALDI-IMS (Invited talk)**

M. Setou

**Vender session: UIVAC-PHI**

T. Miyayama

16:30- Closing remarks

---

**SISS**
*Proudly powered by WordPress.*